



RF Exposure Report

**Test report
On Behalf of
Anker Innovations Limited
For
Soundcore Wakey**

Model No.: A3300

FCC ID: 2AOKB-A3300

Prepared for : Anker Innovations Limited
Room 1318-19, Hollywood Plaza, 610 Nathan Road, Mongkok, Kowloon,
Hongkong

Prepared By : Shenzhen HUAKE Testing Technology Co., Ltd.
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China

Date of Test: Dec. 29, 2018 to Jan. 05, 2019

Date of Report: Jan. 05, 2019

Report Number: HK1901140088EF



TEST RESULT CERTIFICATION

Applicant's name: Anker Innovations Limited
Address.....: Room 1318-19, Hollywood Plaza, 610 Nathan Road, Mongkok, Kowloon, Hongkong
Manufacture's Name.....: Anker Innovations Limited
Address.....: Room 1318-19, Hollywood Plaza, 610 Nathan Road, Mongkok, Kowloon, Hongkong

Factory's Name: Shenzhen Fenda Technology Co., Ltd.
Address.....: Fenda Hi-Tech Park, Zhoushi Road, Shiyan Town, Baoan District, SHENZHEN, Guangdong, China

Product description

Trade Mark: Soundcore
Product name: Soundcore Wakey
Model and/or type reference .: A3300

Standards: KDB 680106 D01 RF Exposure Wireless Charging Base App v03

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Date of Test.....:

Date (s) of performance of tests.....: Dec. 29, 2018 to Jan. 05, 2019

Date of Issue.....: Jan. 05, 2019

Test Result.....: **Pass**

Testing Engineer :

(Gary Qian)

Technical Manager :

(Eden Hu)

Authorized Signatory :

(Jason Zhou)



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1. TEST SUMMARY

1.1 TEST PROCEDURES AND RESULTS

DESCRIPTION OF TEST	RESULT
E and H field strength measurements	Compliant

1.2 TEST FACILITY

Test Firm : Shenzhen HUAKE Testing Technology Co., Ltd.

Address : 1-2/F, Building 19, Junfeng Industrial Park, Chongqing Road,
Heping Community, Fuhai Street, Bao'an District, Shenzhen,
Guangdong, China

IC Registration No.: 21210

FCC Registration No.: CN1229

Test Firm Registration Number : 616276

1.3 MEASUREMENT UNCERTAINTY

Measurement Uncertainty

Conducted Emission Expanded Uncertainty = 2.23dB, k=2

Radiated emission expanded uncertainty(9kHz-30MHz) = 3.08dB, k=2

Radiated emission expanded uncertainty(30MHz-1000MHz) = 4.42dB, k=2

Radiated emission expanded uncertainty(Above 1GHz) = 4.06dB, k=2



2. GENERAL INFORMATION

2.1. PRODUCT DESCRIPTION

A major technical description of EUT is described as following

Operation Frequency	110-205kHz
Maximum field strength	52.96dBuV/m(Peak)@3m
Antenna Designation	Integrated Antenna (Met 15.203 Antenna requirement)
Hardware Version	A3300-01-A0D-T3
Software Version	V1.0
Power Supply	DC 15V by adapter
Max. power of the primary coil	10W

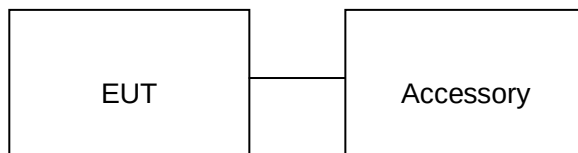


2.2 OPERATION OF EUT DURING TESTING

NO.	TEST MODE DESCRIPTION
1	Wireless charging Mode(Full load)
2	Wireless charging Mode(half load)
3	Wireless charging Mode(Null load)
Note: 1. The mode 1 was the worst case and only the data of the worst case record in this report.	

2.3 DESCRIPTION OF TEST SETUP

Configure :



Item	Equipment	Model No.	ID or Specification	Remark
1	Adapter	DST451-150300W-K	DC 15V3A	Accessory
2	Wireless Load	N/A	10W	Support



3. TEST EQUIPMENT LIST

Description	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Broadband Field Meter	Narda Safety Test Solutions GmbH	NBM-550	J-0004	June 12, 2018	June 11, 2019
Probe FHP	Narda Safety Test Solutions GmbH	EHP-50F	J-0015	June 12, 2018	June 11, 2019



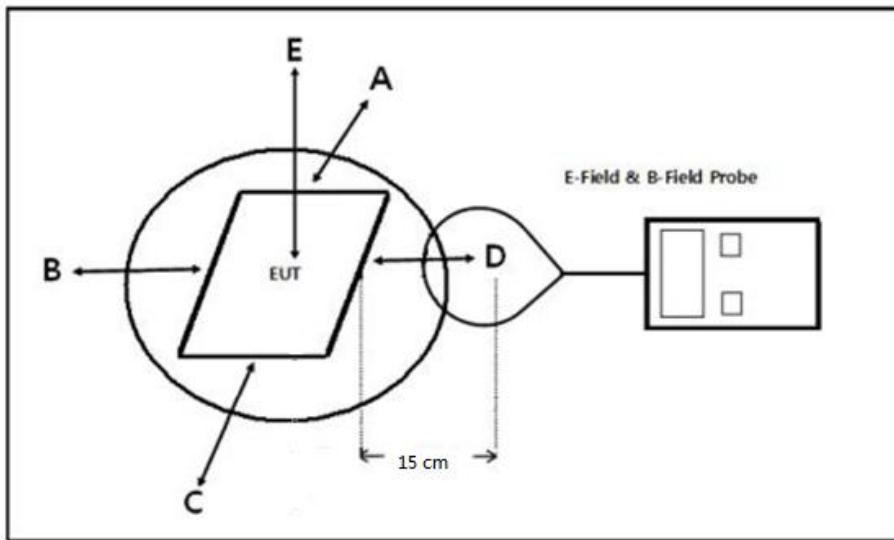
4. RADIO FREQUENCY (RF) EXPOSURE TEST

4.1. LIMITS

For devices designed for typical desktop applications, such as wireless charging pads, RF exposure evaluation should be conducted assuming a user separation distance of 15 cm. E and H field strength measurements or numerical modeling may be used to demonstrate compliance. Measurements should be made from all sides and the top of the primary/client pair, with the 15 cm measured from the center of the probe(s) to the edge of the device. Emissions between 100 kHz to 300 kHz should be assessed versus the limits at 300 kHz in Table 1 of Section 1.1310: 614 V/m and 1.63 A/m.

4.2. TEST SETUP

Position A: Front of EUT; Position B: Left of EUT; Position C: back of EUT; Position D: Right of EUT;
Position E: Top of EUT(20 cm measure distance);





4.3. TEST PROCEDURE

The EUT was placed on a non-conductive table top and the ancillary equipment (e.g. mobile phone) was placed on the EUT for charging.

Maximum E-field and H-field measurements were tested 15cm from each side of the EUT. For top side the measure distance is 15cm.

Along the side of the EUT to center of E-field probe and H-field probe were positioned at the location to search maximum field strength.



4.4. TEST RESULT

Test condition: Mode 1

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	FCC Limit (V/m)	IC Limit (V/m)
118.7kHz	0.16	0.16	0.16	0.16	2.24	614	90

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	FCC Limit (A/m)	IC Limit (A/m)
118.7kHz	0.18	0.18	0.18	0.18	0.45	1.63	90

Test condition: Mode 2

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	FCC Limit (V/m)	IC Limit (V/m)
133.4kHz	0.14	0.14	0.14	0.14	1.71	614	90

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	FCC Limit (A/m)	IC Limit (A/m)
133.4kHz	0.12	0.12	0.12	0.12	0.38	1.63	90



Test condition: Mode 3

E-field strength test result:

Frequency Range	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	FCC Limit (V/m)	IC Limit (V/m)
125.6kHz	0.16	0.16	0.16	0.16	1.50	614	90

H-field strength test result:

Frequency Range	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	FCC Limit (A/m)	IC Limit (A/m)
125.6kHz	0.13	0.13	0.13	0.13	0.25	1.63	90

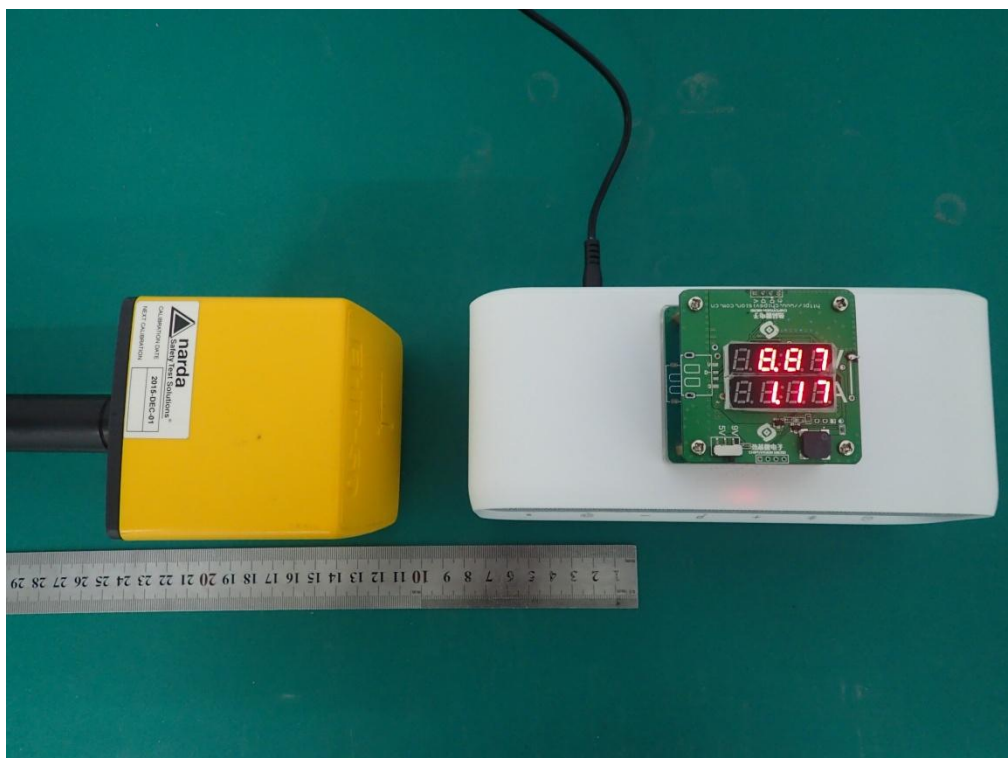


APPENDIX A: PHOTOGRAPHS OF TEST SETUP

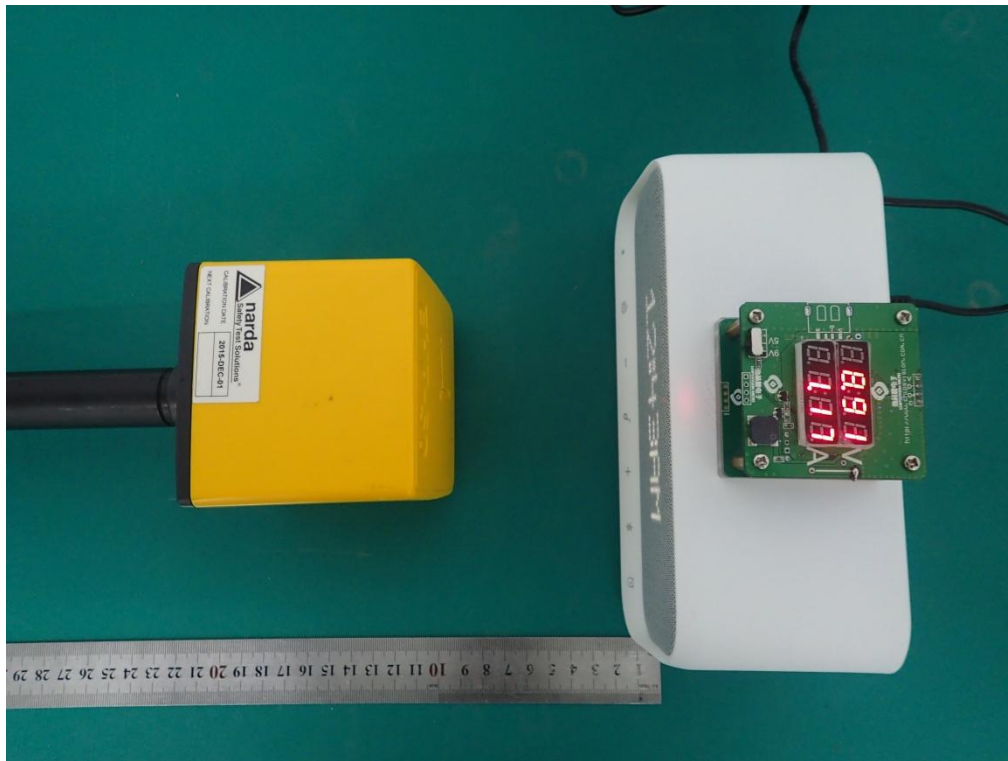
Position E



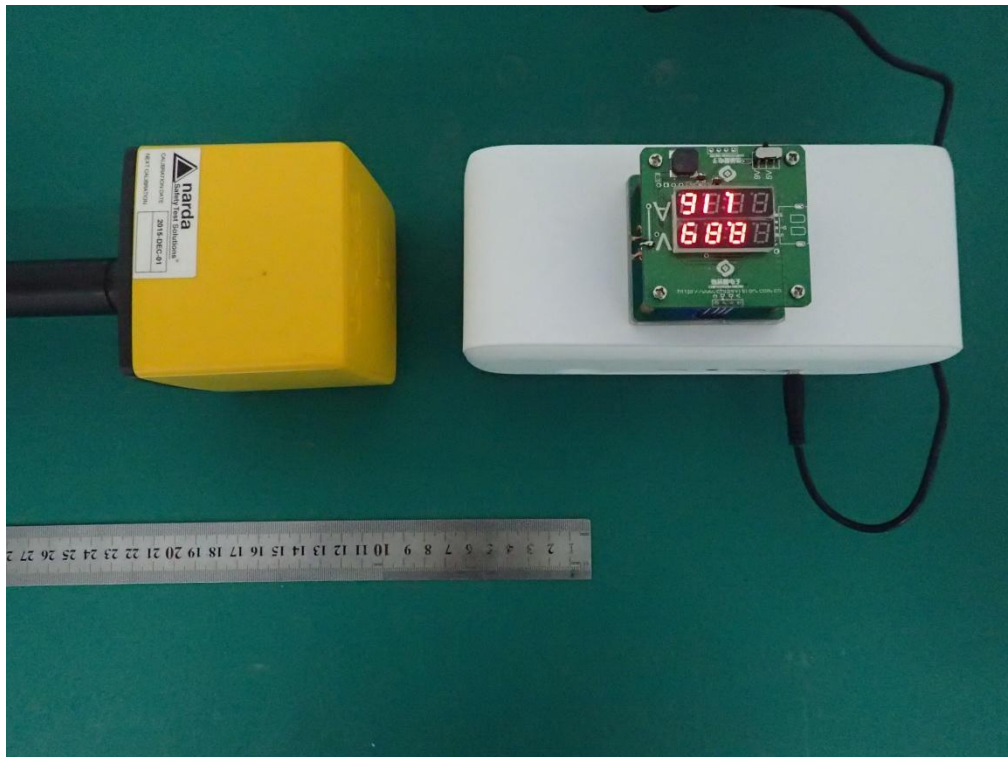
Position A



Position B

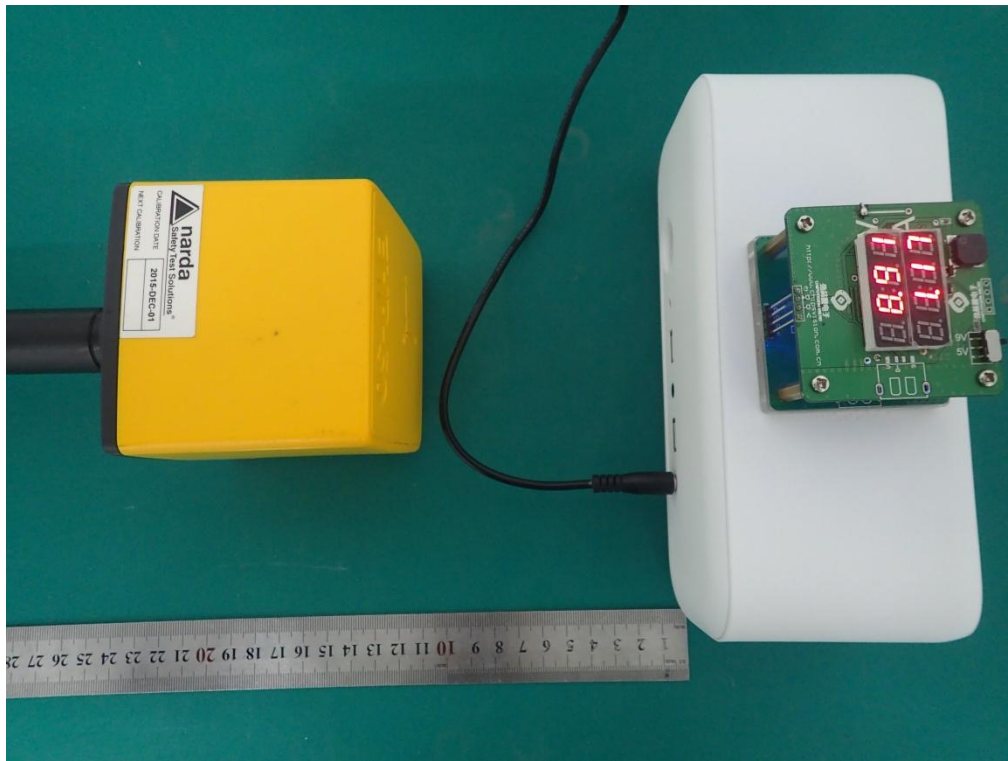


Position C





Position D



----END OF REPORT----